

Title of Change:	Additional wafer fabrication facility for ONBCD25 technology in onsemi Aizu located in Aizu, Japan.			
Proposed Changed Material First Ship Date:	19 Jun 2024 or earlier if approved by customer			
Current Material Last Order Date:	N/A Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.			
Current Material Last Delivery Date:	N/A The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory			
Product Category:	Active components – Integrated circuits			
Contact information:	Contact your local onsemi Sales Office or <u>PCNSupport@onsemi.com</u>			
PCN Samples Contact:	Contact your local onsemi Sales Office to place sample order. Sample requests are to be submitted no later than 45 days after publication of this change notification. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.			
Additional Reliability Data:	Contact your local onsemi Sales Office or Jacob.Saliba@onsemi.com			
Type of Notification:	This is an Initial Product/Process Change Notification (IPCN) sent to customers. An IPCN is an advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan. The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN). This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 6 months prior to implementation of the change. In case of questions, contact < <u>PCN.Support@onsemi.com</u> >.			
Change Category				
Category	Type of Change			
Process - Wafer Production	Move of all or part of wafer fab to a different location/site/subcontractor			
Description and Purpose:				
	From	То		
Fab Site	onsemi Gresham, US	onsemi Gresham, US or onsemi Aizu, Japan		
There is no product marking change as a result of this change				
Reason / Motivation for Change:	Capacity improvement			
Anticipated impact on fit, form, function, reliability, product safety or manufacturability:	The device will be qualified and validated based on the same Product Specification. No anticipated impacts.			



onsemi Sites		External Foundry/Subcon Sites	
onsemi Aizu, Japan		None	
arking of Parts/ Traceability of Change:	No change to marking / Changed material may be identified by date code		
eliability Data Summary:			
/ DEVICE NAME: NCV6324BMTAAWTBG			
/ DEVICE NAME: NCV6324BMTAAWTBG MS: S90590 NCKAGE: WDFN8 AU SNGL HPBF WFS	Specification	Condition	Intorval
/ DEVICE NAME: NCV6324BMTAAWTBG MS: S90590 NCKAGE: WDFN8 AU SNGL HPBF WFS Test	Specification	Condition	Interval
V DEVICE NAME: NCV6324BMTAAWTBG MS: S90590 ACKAGE: WDFN8 AU SNGL HPBF WFS Test High Temperature Operating Life	Specification JESD22-A108 JESD22-A103	Condition Ta=125°C, 100 % max rated Vcc Ta= 150°C	Interval 1008 hrs 1008 brs
/ DEVICE NAME: NCV6324BMTAAWTBG MS: S90590 ACKAGE: WDFN8 AU SNGL HPBF WFS Test High Temperature Operating Life High Temperature Storage Life Early Life Failure Rate	Specification JESD22-A108 JESD22-A103 JESD22-A108	Condition Ta=125°C, 100 % max rated Vcc Ta= 150°C Ta=125°C, 100 % max rated Vcc	Interval 1008 hrs 1008 hrs 48 hrs
V DEVICE NAME: NCV6324BMTAAWTBG MS: S90590 ACKAGE: WDFN8 AU SNGL HPBF WFS Test High Temperature Operating Life High Temperature Storage Life Early Life Failure Rate Preconditioning	Specification JESD22-A108 JESD22-A103 JESD22-A108 J-STD-020 JESD-A113	Condition Ta=125°C, 100 % max rated Vcc Ta= 150°C Ta=125°C, 100 % max rated Vcc MSL 1 @ 260 °C	Interval 1008 hrs 1008 hrs 48 hrs
V DEVICE NAME: NCV6324BMTAAWTBG MS: S90590 ACKAGE: WDFN8 AU SNGL HPBF WFS Test High Temperature Operating Life High Temperature Storage Life Early Life Failure Rate Preconditioning Temperature Cycling	Specification JESD22-A108 JESD22-A103 JESD22-A108 J-STD-020 JESD-A113 JESD22-A104	Condition Ta=125°C, 100 % max rated Vcc Ta= 150°C Ta=125°C, 100 % max rated Vcc MSL 1 @ 260 °C Ta= -65°C to +150°C	Interval 1008 hrs 1008 hrs 48 hrs 1000 cyc
V DEVICE NAME: NCV6324BMTAAWTBG MS: S90590 ACKAGE: WDFN8 AU SNGL HPBF WFS Test High Temperature Operating Life High Temperature Storage Life Early Life Failure Rate Preconditioning Temperature Cycling Highly Accelerated Stress Test	Specification JESD22-A108 JESD22-A103 JESD22-A108 J-STD-020 JESD-A113 JESD22-A104 JESD22-A110	Condition Ta=125°C, 100 % max rated Vcc Ta= 150°C Ta=125°C, 100 % max rated Vcc MSL 1 @ 260 °C Ta= -65°C to +150°C 130°C, 85% RH, 18.8psig, bias	Interval 1008 hrs 1008 hrs 48 hrs 1000 cyc 96 hrs

Electrical characteristics are not impacted.

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the <u>PCN Customized Portal</u>.

Current Part Number	New Part Number	Qualification Vehicle
NCV6323BMTAATBG	N/A	NCV6324BMTAAWTBG
NCV6323BMTAAWTBG	N/A	NCV6324BMTAAWTBG
NCV6323DMTAATBG	N/A	NCV6324BMTAAWTBG
NCV6323DMTAAWTBG	N/A	NCV6324BMTAAWTBG
NCV6324BMTAATBG	N/A	NCV6324BMTAAWTBG
NCV6324BMTAAWTBG	N/A	NCV6324BMTAAWTBG